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Sommario/riassunto	Reports on recent concepts, methodologies, and trends in testing electronic circuits and systems to meet the challenges of a wider range of capabilities being integrated into compact products, and the higher quality being demanded. Some 90 papers explore such aspects as designing for testability, on-line testing, volume manufacturing, sequential circuits, multi-chip modules and memory testing, non-traditional approaches, fault simulation and test generation, and built-in self-tests. No subject index. Annotation copyright by Book News, Inc., Portland, OR.